

R E M A R K S

Careful review and examination of the subject application are noted and appreciated.

SUPPORT FOR CLAIM AMENDMENTS

Support for the amendments to the claims can be found in the drawings as originally filed, for example, on FIGS. 3-6 and in the specification as originally filed, for example, on page 7, line 10 through page 24, line 24 and on page 25, line 1 through page 26, line 4. As such, no new matter has been added.

CLAIM REJECTIONS UNDER 35 U.S.C. §102

The rejection of claims 1, 3-4, 10, 12, 16, 17, 20-22 and 24-26 under 35 U.S.C. §102(b) as being anticipated by Uchida '304 (hereinafter Uchida) is respectfully traversed and should be withdrawn.

The Federal Circuit has stated that "[t]o anticipate, every element and limitation of the claimed invention must be found in a single prior art reference, arranged as in the claim."¹ The Federal circuit has added that the anticipation determination is viewed from one of ordinary skill in the art: "There must be no

¹ *Brown v. 3M*, 60 USPQ2d 1375, 1376 (Fed. Cir. 2001) citing *Karsten Mfg. Corp. v. Cleveland Golf Co.*, 242 F.3d 1376, 1383, 58 USPQ2d 1286, 1291 (Fed. Cir. 2001); *Scripps Clinic & Research Found. v. Genentech Inc.*, 927 F.2d 1565, 18 U.S.P.Q.2d 1001, 1010 (Fed. Cir. 1991) (Emphasis added by Appellants).

difference between the claimed invention and the reference disclosure, as viewed by a person of ordinary skill in the field of the invention."² As explained herein below, because Uchida does not disclose or suggest a logic circuit configured to generate a plurality of identification codes in response to a logical combination of (i) one or more voltage levels on one or more pins, (ii) a state of one or more bond options AND (iii) a state of one or more metal options as presently claimed, Uchida does not anticipate the presently claimed invention. As such, the rejection should be withdrawn.

Uchida is directed to a semiconductor integrated circuit (title). Uchida describes selecting an identification code for a device via the diffusion process and bond optioning bonding pads to a GND pin during assembly (see column 3, line 58 through column 4, line 5 and column 6, lines 14-33 of Uchida). Since Uchida determines an identification code using only the diffusion process and bond options, it follows that Uchida does not disclose or suggest a logic circuit configured to generate a plurality of identification codes in response to a logical combination of (i) one or more voltage levels on one or more pins, (ii) a state of one or more bond options AND (iii) a state of one or more metal options, as presently claimed. Therefore, Uchida does not disclose

² *Scripps Clinic & Research Found. v. Genentech Inc.*, 927 F.2d 1565, 18 U.S.P.Q.2d 1001, 1010 (Fed. Cir. 1991).

or import each and every element of the presently claimed invention, arranged as in the claims. As such, the presently claimed invention is fully patentable over the Uchida and the rejection should be withdrawn.

Furthermore, assuming, arguendo, that (i) elements 6 and 7 of Uchida are similar to the presently claimed bond options, (ii) GND in element 4, VCC in element 5, and elements 31 and 32 of Uchida are similar to the presently claimed metal options and (iii) elements 9 and 10 of Uchida are similar to the pins for receiving the one or more voltage levels as presently claimed (as suggested on page 2, section 4 of the Office Action and for which Applicant's representative does not necessarily agree), Uchida does not disclose or suggest each and every element of the presently claimed invention, arranged as in the present claims. In particular, the Office Action presents no evidence or convincing line of reasoning why one of ordinary skill in the field of the present invention would consider elements 9 and 10 of Uchida as having no differences from the presently claimed one or more voltage levels on the one or more pins which are logically combined with (i) the state of one or more bond options AND (iii) the state of one or more metal options to generate the ID codes.

Specifically, the elements 9 and 10 of Uchida are described as a shift clock input pad and a ID code setting pad, respectively (column 5, lines 23-36 of Uchida). The signal

presented at the element 10 loads an ID code into a shift register formed by elements 4 and 5 of Uchida (see FIG. 2 and column 6, lines 53-56 of Uchida). The signal presented to the element 9 of Uchida serializes the ID code by shifting the code through the shift register formed by elements 4 and 5 of Uchida (see FIGS. 2, 4, 8 and 9 and column 6, line 51 through column 7, line 5 of Uchida). In particular, Uchida states:

Here, when the signal for the ID setting pad 10 is turned into high level, the multiplexers 41 to 43 output the levels of A-terminals to the O-terminal. Next, when the shift clock to the shift clock pad 9 is turned into high level, high level is held in the F/F 51, low level is held in the F/F 52, high level held in the F/F 53, low level is held the F/F 54, and then high level is output from the ID code output pad 8.

After turning the signal for the ID code setting pad 10 into low level, when shift clock for three clocks is input to the shift clock pad 9, low level, low level and high level are output in order from the ID code output pad 8.

At this time, by setting so that the ID code is output sequentially in an order from the least significant bit (LSB) to the most significant bit (MSB), the ID code "1001" can be output as the ID code for the kind C.

Similarly, for remaining kinds A, B and D, the ID codes respectively corresponding thereto can be output depending upon whether the bonding option pads 6 and 7 are bonded to the GND pins. (column 6, line 51 through column 7, line 5 of Uchida).

One skilled in the field of the invention would not consider (i) a voltage level at the pad 10 of Uchida which loads an ID code predetermined by the diffusion process and bond options into the

shift register formed by elements 4 and 5 of Uchida and (ii) a voltage level at the shift clock input pad 9 of Uchida which shifts the predetermined ID code through the shift register formed by elements 4 and 5 of Uchida to be the same as the presently claimed one or more voltage levels on one or more pins which are logically combined with the state of one or more bond options and the state of one or more metal options to generate a plurality of identification codes, as presently claimed. The Office Action appears to confuse generating the ID codes, as presently claimed, with presenting already generated ID codes as performed by the elements 9 and 10 of Uchida.

Furthermore, Uchida does not disclose or suggest generalizing an ID code by logically combining (i) one or more voltage levels on one or more pins, (ii) a state of one or more bond options **AND** (iii) a state of one or more metal options, as presently claimed. Specifically, the ID codes generated by the circuit of Uchida are determined **ONLY** by the bond option pads 6 and 7 and logic levels set in the diffusion process. In particular, Uchida states:

For instance, in the diffusion process, the ID code becomes "10XX[.]". In this ID code, X is "0" or "1" which is determined whether the bonding option pads 6 and 7 are bonded to the GND pins or not (column 6, lines 14-17 of Uchida, emphasis added).

Uchida is silent regarding logically combining voltage levels at pins 9 and 10 with a state of the bond option pads 6 and 7 and the

voltage levels set in the diffusions process to generate ID codes. With respect to generating the ID codes, Uchida further states:

When the bonding option pads 6 and 7 are both bonded to the GND pins (step S4 of FIG. 3), the IC chip becomes a kind A (step S5 of FIG. 3) and then the ID code becomes "1000".

On the other hand, when only bonding option pad 6 is bonded to the GND pin (step S6 of FIG. 3), IC chip becomes a kind B (step S7 of FIG. 3) and then the ID code becomes "1010".

Also, when only bonding option pad 7 is bonded to the GND pin (step S8 of FIG. 3), IC chip becomes a kind C (step S9 of FIG. 3) and then the ID code becomes "1001".

When the bonding option pads 6 and 7 are both not bonded to the GND pins (step S10 of FIG. 3), IC chip becomes a kind D (step S11 of FIG. 3) and then the ID code becomes "1011" (column 6, lines 18-33 of Uchida).

Since each bit of the ID codes of Uchida is directly determined by a respective bond option or diffusion, it follows that Uchida does not disclose or suggest generating an ID code by logically combining (i) one or more voltage levels on one or more pins, (ii) a state of one or more bond options AND (iii) a state of one or more metal options, as presently claimed.

The specification provides, for example on pages 14-24, numerous examples of identification codes generated by logically combining (i) one or more voltage levels on one or more pins, (ii) a state of one or more bond options AND (iii) a state of one or more metal options, as presently claimed. The Office Action presents no evidence or convincing line of reasoning why one of ordinary skill in the field of the present invention would consider

the circuit of Uchida as having no differences from the logic circuit configured to generate a plurality of IP codes in response to a logical combination of (i) one or more voltage levels on one or more pins, (ii) a state of one or more bond options AND (iii) a state of one or more metal options, as presently claimed.

Furthermore, the conclusory statement on page 4, lines 22-26 of the Office Action that:

. . . the logical combination of (i) through (iii) is comprised of the combination of elements 6-7 (bonding options), one or more voltage levels (elements 9 or 10); and a state of one or more metal options (elements 31, 32 or GND [sic; GND] in element 4 or VDD in element 5).

does not address (i) what the alleged combination is or (ii) why the alleged combination of signals would be considered by one of skill in the art of the present invention as a logical combination, as presently claimed (see page 4, lines 22-26 of the Office Action). The Office Action appears to be trying to shift the burden to the Applicants to prove a negative (i.e., that the signals are not logically combined) rather than meeting the Office's burden to factually establish that one skilled in the art would view the disclosure of Uchida as having no differences from the presently claimed invention.

Furthermore, the interpretation of the elements 31 and 32 of Uchida as being the same as the presently claimed metal options is not technically correct. Specifically, Uchida states:

In FIG. 2, the bonding judgement portion 3 comprises P-channel transistors 31 and 32. P-channel transistors 31 and 32 are set at small current capacity so that they may serve as pull-up resistance for the signal lines 101 and 102 from the bonding option pads 6 and 7 to the function circuit portion and the ID setting portion by connecting the gates thereof to the GND level (column 6, lines 43-50 of Uchida, emphasis added).

Rather than being separate options from the bond options, as presently claimed, the elements 31 and 32 of Uchida are an integral part of the bond option capability of elements 6 and 7. In particular, elements 31 and 32 allow the signal lines 101 and 102, respectively, to become high when the bond option pads 6 and 7 are not bonded to the GND pin (see column 6, lines 46-49 of Uchida).

In contrast to Uchida, the presently claimed invention (claim 1) provides a logic circuit configured to generate a plurality of identification (ID) codes in response to a logical combination of (i) one or more voltage levels on one or more pins, (ii) a state of one or more bond options AND (iii) a state of one or more metal options. Claims 16 and 20 include similar limitations. Uchida does not disclose or suggest a logic circuit configured to generate a plurality of identification codes in response to a logical combination of (i) one or more voltage levels on one or more pins, (ii) a state of one or more bond options AND (iii) a state of one or more metal options, as presently claimed. Therefore, Uchida does not disclose or suggest each and every element of the presently claimed invention, arranged as in the

claims. As such, the presently claimed invention is fully patentable over Uchida and the rejection should be withdrawn.

Furthermore, with respect to claim 16, the Office Action on page 3, last line, associates elements 6 and 7 with the presently claimed one or more pins and on page 4, lines 5-6 associates elements 6 and 7 with the presently claimed bonding options. Clearly, if elements 6 and 7 correspond to the presently claimed one or more pins, it follows that elements 6 and 7 cannot be the one or more bonding options. Alternatively, if elements 6 and 7 correspond to the presently claimed one or more bonding options, it follows that elements 6 and 7 cannot correspond also to the presently claimed one or more pins. As such, the Office Action fails to factually support a *prima facie* conclusion of anticipation. Therefore, the presently claimed invention is fully patentable over the cited reference and the rejection should be withdrawn.

Claims 2, 4-15, 17-19 and 21-26 depend, either directly or indirectly, from claims 1 or 16 which are believed to be allowable. As such, the presently claimed invention is fully patentable over Uchida and the rejections should be withdrawn.

CLAIM REJECTIONS UNDER 35 U.S.C. §103

The rejection of claims 2 and 5-9 under 35 U.S.C. §103 (a) as being obvious over Uchida in view of "THER Standard Test Access

Test and Boundary Scan Architecture, IEEE Std 1149.1-1990" (hereinafter IEEE Std 1149.1-1990) is respectfully traversed and should be withdrawn.

The rejection of claims 11, 13 and 14 under 35 U.S.C. §103(a) as being obvious over Uchida in view of Carmichael et al. '311 (hereinafter Carmichael) is respectfully traversed and should be withdrawn.

The rejection of claim 15 and 23 under 35 U.S.C. §103(a) as being obvious over Uchida in view of Carmichael and further in view of Warger et al. '246 (hereinafter Warger) is respectfully traversed and should be withdrawn.

The rejection of claims 18 and 19 under 35 U.S.C. §103(a) as being obvious over Uchida in view of IBM and further in view of "IEEE Standard Test Access Port and Boundary Scan Architecture, IEEE Std 1149.1-1990" (hereinafter IEEE Std 1149.1-1990) is respectfully traversed and should be withdrawn.

Claims 3, 4, 15, 17-19 and 21-26 depend, either directly or indirectly, from claims 1 or 16 which are believed to be allowable. As such, the presently claimed invention is fully patentable over the cited references and the rejections should be withdrawn.

Accordingly, the present application is in condition for allowance. Early and favorable action by the Examiner is respectfully solicited.

The Examiner is respectfully invited to call the Applicant's representative should it be deemed beneficial to further advance prosecution of the application.

If any additional fees are due, please charge our office Account No. 50-0541.

Respectfully submitted,

CHRISTOPHER P. MAIORANA, P.C.

Robert M. Miller
Robert M. Miller
Registration No. 42,892
24840 Harper Avenue, Suite 100
St. Clair Shores, MI 48080
(586) 498-0670

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